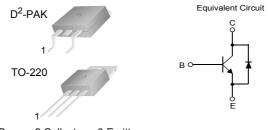


May 2010

# KSC5338D/KSC5338DW NPN Triple Diffused Planar Silicon Transistor

### **Features**

- · High Voltage Power Switch Switching Application
- · Wide Safe Operating Area
- Built-in Free-Wheeling Diode
- · Suitable for Electronic Ballast Application
- · Small Variance in Storage Time
- Two Package Choices: TO-220 or D2-PAK



1.Base 2.Collector 3.Emitter

## Absolute Maximum Ratings T<sub>a</sub>=25°C unless otherwise noted

Symbol	Parameter	Value	Units
V <sub>CBO</sub>	Collector-Base Voltage	1000	V
$V_{CEO}$	Collector-Emitter Voltage	450	V
V <sub>EBO</sub>	Emitter-Base Voltage	12	V
I <sub>C</sub>	Collector Current (DC)	5	Α
I <sub>CP</sub>	*Collector Current (Pulse)	10	Α
I <sub>B</sub>	Base Current (DC)	2	Α
I <sub>BP</sub>	*Base Current (Pulse)	4	Α
P <sub>C</sub>	Power Dissipation (T <sub>C</sub> =25°C)	75	W
T <sub>J</sub>	Junction Temperature	150	°C
T <sub>STG</sub>	Storage Temperature	- 55 to 150	°C

<sup>\*</sup> Pulse Test : Pulse Width = 5ms, Duty Cycle ≤ 10%

## **Thermal Characteristics**

Symbol	Parameter		Rating	Units
$R_{ heta jc}$	Thermal Resistance	Junction to Case	1.65	°C/W
$R_{ hetaja}$	Thermal Nesistance	Junction to Ambient	62.5	°C/W
T <sub>L</sub>	Maximum Lead Temperature for Soldering		270	°C

# $\textbf{Electrical Characteristics} \quad \textbf{T}_{a} \text{=} 25^{\circ} \text{C unless otherwise noted}$

Symbol	Parameter	Test Condition		Min.	Тур.	Max.	Units
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	I <sub>C</sub> =1mA, I <sub>E</sub> =0		1000			V
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	I <sub>C</sub> =5mA, I <sub>B</sub> =0		450			V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	I <sub>E</sub> =1mA, I <sub>C</sub> =0		12			V
I <sub>CBO</sub>	Collector Cut-off Current	V <sub>CB</sub> =800V, I <sub>E</sub> =0				10	μΑ
I <sub>CES</sub>	Collector Cut-off Current	V <sub>CES</sub> =1000V, I <sub>EB</sub> =0	T <sub>a</sub> =25°C			100	μΑ
			T <sub>a</sub> =125°C			500	μΑ
I <sub>CEO</sub>	Collector Cut-off Current	V <sub>CE</sub> =450V, I <sub>B</sub> =0	T <sub>a</sub> =25°C			100	μΑ
			T <sub>a</sub> =125°C			500	μΑ
I <sub>EBO</sub>	Emitter Cut-off Current	V <sub>EB</sub> =10V, I <sub>C</sub> =0				10	μΑ
h <sub>FE</sub>	DC Current Gain	V <sub>CE</sub> =1V, I <sub>C</sub> =0.8A	T <sub>a</sub> =25°C	15	25		
			T <sub>a</sub> =125°C	10	14		
		V <sub>CE</sub> =1V, I <sub>C</sub> =2A	T <sub>a</sub> =25°C	6	9		
		02 7 0	T <sub>a</sub> =125°C	4	6		
		V <sub>CE</sub> =2.5V, I <sub>C</sub> =1A	T <sub>a</sub> =25°C	18	25		
			T <sub>a</sub> =125°C	14	18		
V <sub>CE</sub> (sat)	Collector-Emitter Saturation Voltage	I <sub>C</sub> =0.8A, I <sub>B</sub> =0.08A			0.35	0.5	V
OL( )	Ĭ		T <sub>a</sub> =125°C		0.55	0.75	V
		I <sub>C</sub> =2A, I <sub>B</sub> =0.4A	T <sub>a</sub> =25°C		0.47	0.75	V
		, ,	T <sub>a</sub> =125°C		0.9	1.1	V
		I <sub>C</sub> =0.8A, I <sub>B</sub> =0.04A	-		0.9	1.5	V
		10 0.07 t, 18 0.0 17 t	T <sub>a</sub> =125°C		1.8	2.5	V
		I <sub>C</sub> =1A, I <sub>B</sub> =0.2A	T <sub>a</sub> =25°C		0.22	0.5	V
			T <sub>a</sub> =125°C		0.3	0.6	V
V <sub>BE</sub> (sat)	Base-Emitter Saturation Voltage	I <sub>C</sub> =0.8A, I <sub>B</sub> =0.08A			0.8	1.0	V
DL( )	Dado Emilior Galardion Vollage	ic over the control	T <sub>a</sub> =125°C		0.65	0.9	V
		I <sub>C</sub> =2A, I <sub>B</sub> =0.4A	T <sub>a</sub> =25°C		0.9	1.0	V
			T <sub>a</sub> =125°C		0.8	0.9	V
C <sub>ib</sub>	Input Capacitance	V <sub>EB</sub> =10V, I <sub>C</sub> =0.5A, f=1MHz			550	750	pF
C <sub>ob</sub>	Output Capacitance	V <sub>CB</sub> =10V, I <sub>E</sub> =0, f=1			60	100	pF
f <sub>T</sub>	Current Gain Bandwidth Product	I <sub>C</sub> =0.5A,V <sub>CE</sub> =10V			11		MHz
V <sub>F</sub>	Diode Forward Voltage		T <sub>a</sub> =25°C		0.86	1.3	V
'			T <sub>a</sub> =125°C		0.79		V
		I <sub>F</sub> =2A	T <sub>a</sub> =25°C		0.95	1.5	V
			T <sub>a</sub> =125°C		0.88		V
t <sub>fr</sub>	Diode Forward Recovery Time (di/dt=10A/μs)	I <sub>F</sub> =0.4A	l d		460		ns
"		I <sub>F</sub> =1A			360		ns
		I <sub>F</sub> =2A	_		325		ns
$V_{CE(DSAT)}$	Dynamic Saturation Voltage	I <sub>C</sub> =1A, I <sub>B1</sub> =100mA	T <sub>a</sub> =25°C		8		V
		V <sub>CC</sub> =300V at 1 μs	T <sub>a</sub> =125°C		15		V
		I <sub>C</sub> =1A, I <sub>B1</sub> =100mA	-		2.9		V
		I <sub>C</sub> =2A, I <sub>B1</sub> =400mA	T <sub>a</sub> =125°C		8		V
			-		9		V
			T <sub>a</sub> =125°C		17		V
		I <sub>C</sub> =2A, I <sub>B1</sub> =400mA V <sub>CC</sub> =300V at 3 μs	_ ~		1.9		V
			T <sub>a</sub> =125°C		8.5		V

# 

Symbol	Parameter	Test Condition		Min	Тур.	Max.	Units
RESISTIVE	LOAD SWITCHING (D.C < 10%, Puls	e Width=40μs)					•
t <sub>ON</sub>	Turn On Time	I <sub>C</sub> =2.5A, I <sub>B1</sub> =500mA,			500	750	ns
t <sub>STG</sub>	Storage Time	I <sub>B2</sub> =-1A, V <sub>CC</sub> =250V,	$R_L = 100\Omega$	1.2		1.5	μS
t <sub>F</sub>	Fall Time				100	200	ns
t <sub>ON</sub>	Turn On Time	I <sub>C</sub> =2A,	T <sub>a</sub> =25°C		100	150	ns
		I <sub>B1</sub> =400mA,	T <sub>a</sub> =125°C		150		ns
t <sub>STG</sub>	Storage Time	I <sub>B2</sub> =-1A, V <sub>CC</sub> =300V,	T <sub>a</sub> =25°C		1.4	2.2	μS
		$R_1 = 150\Omega$	T <sub>a</sub> =125°C		1.7		μS
t <sub>F</sub>	Fall Time		T <sub>a</sub> =25°C		90	150	ns
			T <sub>a</sub> =125°C		150		ns
t <sub>ON</sub>	Turn On Time	I <sub>C</sub> =2.5A,	T <sub>a</sub> =25°C		120	150	ns
		I <sub>B1</sub> =500mA,	T <sub>a</sub> =125°C		150		ns
t <sub>STG</sub>	Storage Time	I <sub>B2</sub> =-5mA, V <sub>CC</sub> =300V,	T <sub>a</sub> =25°C	1.8		2.1	μS
		$R_{l} = 120\Omega$	T <sub>a</sub> =125°C		2.6		μS
t <sub>F</sub>	Fall Time		T <sub>a</sub> =25°C		110	150	ns
			T <sub>a</sub> =125°C		160		ns
INDUCTIVE	LOAD SWITCHING (V <sub>CC</sub> =15V)						•
t <sub>STG</sub>	Storage Time	I <sub>C</sub> =2.5A,	T <sub>a</sub> =25°C		1.9	2.2	μS
		I <sub>B1</sub> =500mA,	T <sub>a</sub> =125°C		2.4		μS
t <sub>F</sub>	Fall Time	I <sub>B2</sub> =-0.5A, V <sub>7</sub> =350V,	T <sub>a</sub> =25°C		160	200	ns
		L <sub>C</sub> =300μH	T <sub>a</sub> =125°C		330		ns
t <sub>C</sub>	Cross-over Time		T <sub>a</sub> =25°C		350	500	ns
			T <sub>a</sub> =125°C		750		ns
t <sub>STG</sub>	Storage Time	I <sub>C</sub> =2A,	T <sub>a</sub> =25°C	1.95		2.25	μS
		I <sub>B1</sub> =400mA,	T <sub>a</sub> =125°C		2.9		μS
t <sub>F</sub>	Fall Time	I <sub>B2</sub> =-0.4A, V <sub>7</sub> =300V,	T <sub>a</sub> =25°C		120	150	ns
		V <sub>Z</sub> =300V, L <sub>C</sub> =200μH	T <sub>a</sub> =125°C		270		ns
t <sub>C</sub>	Cross-over Time	] -0	T <sub>a</sub> =25°C		300	450	ns
		-	T <sub>a</sub> =125°C		700		ns
t <sub>STG</sub>	Storage Time	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	_		0.6	0.8	μS
				1.0		μS	
t <sub>F</sub>	raii Tiffie		T <sub>a</sub> =25°C		70		ns
•				110		ns	
t <sub>C</sub>	Cross-over Time		T <sub>a</sub> =25°C		80	130	ns
			T <sub>a</sub> =125°C		170		ns

## **Typical Characteristics**

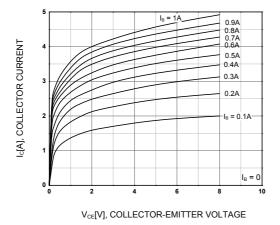


Figure 1. Static Characteristic

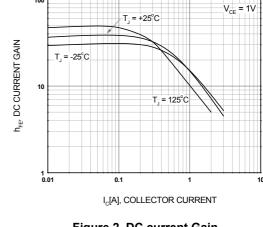


Figure 2. DC current Gain

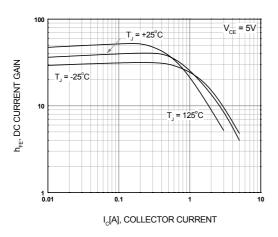


Figure 3. DC current Gain

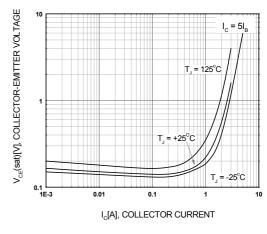


Figure 4. Collector-Emitter Saturation Voltage

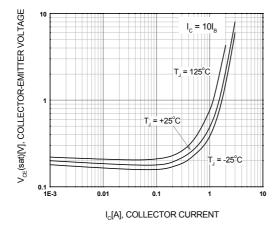


Figure 5. Collector-Emitter Saturation Voltage

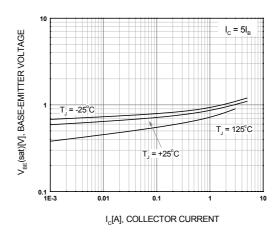


Figure 6. Base-Emitter Saturation Voltage

## Typical Characteristics (Continued)

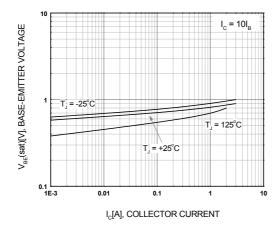


Figure 7. Base-Emitter Saturation Voltage

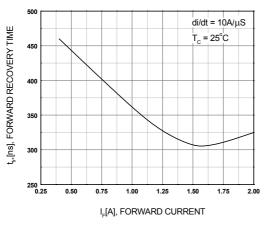


Figure 9. Forward Recovery Time

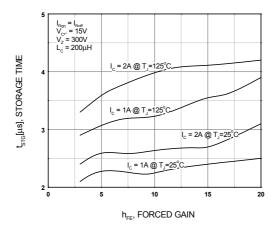
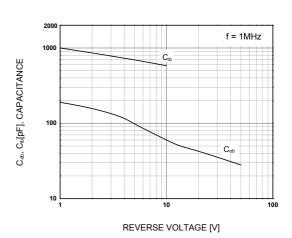


Figure 11. Induction Storage Time



**Figure 8. Collector Output Capacitance** 

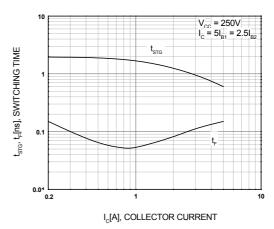
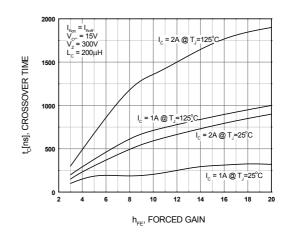


Figure 10. Switching Time



**Figure 12. Inductive Crossover Time** 

## Typical Characteristics (Continued)

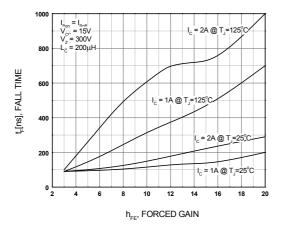


Figure 13. Inductive Fall Time

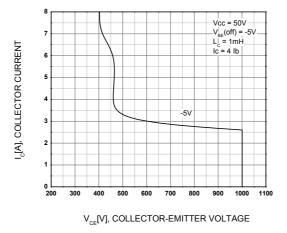


Figure 15. Reverse Bias Safe Operating

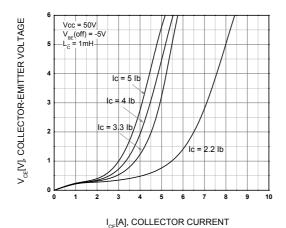


Figure 17. RBSOA Saturation

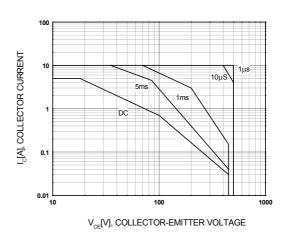


Figure 14. Safe Operating Area

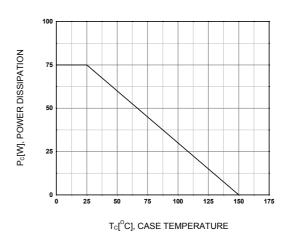
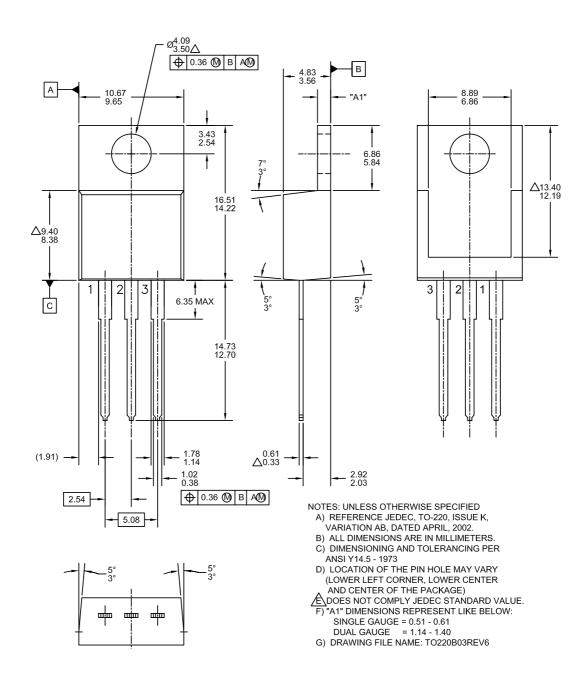


Figure 16. Power Derating

## **Physical Dimensions**

## TO-220



Dimensions in Millimeters





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